Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
10/721,911	TAKAYA CHIBA
Examiner	Art Unit
DINH T. LE	2816

SEARCHED				
Class	Subclass	Date	Examiner	
327	156-158, 231, 256, 257	5/22/2005	DL	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	1	<u> </u>		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST	5/22/2005	DL